

Examiner-Initiated Interview Summary

Application No.

09/699,772

Applicant(s)

SUTARDJA, SEHAT

Examiner

Arnold M Kinkead

Art Unit

2817

All Participants:(1) Arnold M Kinkead.(2) Mr. Donald Daley.**Status of Application:** _____(3) Mr. Eric Janofsky.

(4) _____

Date of Interview: 9 October 2003**Time:** _____**Type of Interview:**

- ☒ Telephonic
☐ Video Conference
☐ Personal (Copy given to: ☐ Applicant ☐ Applicant's representative)

Exhibit Shown or Demonstrated: ☐ Yes ☒ No

If Yes, provide a brief description:

Part I.

Rejection(s) discussed:

Claims discussed:

all pending, notably 2,15, and 57

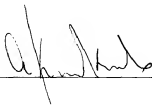
Prior art documents discussed:

*Beards et al of record***Part II.**

SUBSTANCE OF INTERVIEW DESCRIBING THE GENERAL NATURE OF WHAT WAS DISCUSSED:

*See Continuation Sheet***Part III.**

- ☒ It is not necessary for applicant to provide a separate record of the substance of the interview, since the interview directly resulted in the allowance of the application. The examiner will provide a written summary of the substance of the interview in the Notice of Allowability.
- ☐ It is not necessary for applicant to provide a separate record of the substance of the interview, since the interview did not result in resolution of all issues. A brief summary by the examiner appears in Part II above.



(Examiner/SPE Signature)

(Applicant/Applicant's Representative Signature – if appropriate)

Continuation of Substance of Interview including description of the general nature of what was discussed: The examiner reviewed the Beards et al reference, col. 4, lines 6-55, noting the fact that it does in fact suggest use of FET's and that that the degeneration/attenuation capacitance is used to prevent low frequency noise, in FET's, this would inherently include flicker noise too. note fundamental frequency of 1000MHz is 10 times the 100MHz of the bandpass filter formed by the attenuating device and amplifier (ll. 35-40). 112, 2nd para issues resolved for claims too. (see exam. amdt.)